## Notice of References Cited Application/Control No. | Applicant(s)/Patent Under Reexamination SAKAGUCHI ET AL. Examiner | Art Unit | Page 1 of 1

## **U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	Α	US-2004/0115370	06-2004	Funakoshi et al.	428/032.1
	В	US-			
	С	US-			·
	D	US-			
	Е	US-			
	F	US-			
	G	US-			
	H	US-			
	_	US-			
	J	US-			
	К	US-			
	L	US-			
	М	US-			

## **FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N &	WO 2085634 A1	10-2002	World Intellect	FUNAKOSHI et al.	B41M 05/00
	0					
	Р					
	Q			·		
	R					
	s					
	Т					

## **NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)						
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